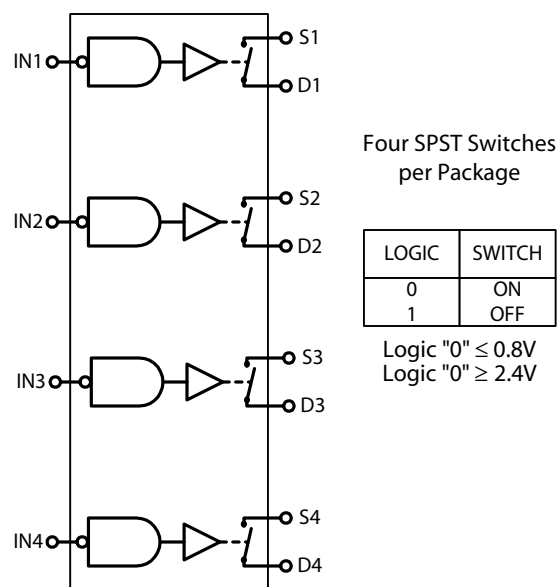
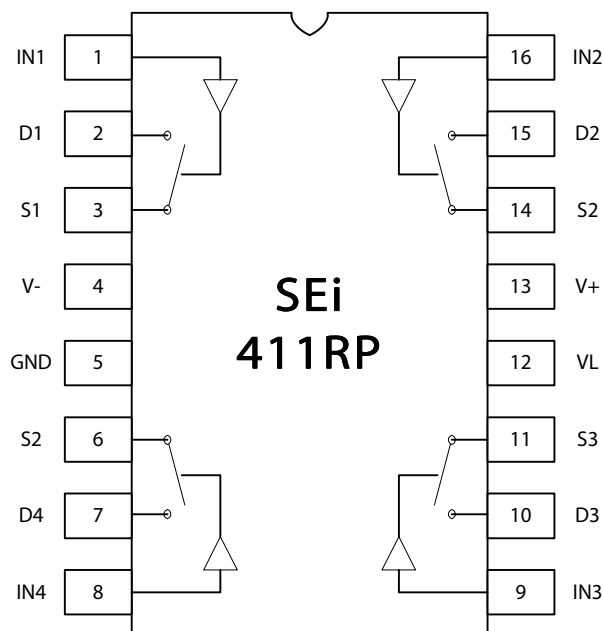




## FEATURES:

- Quad SPST CMOS Analog Switch
- 44-V Supply Max Rating
- RAD-PAK® radiation hardened against natural space radiation
- Total Dose Hardness: consult factory for TID
- Package : 16 pin RAD-PAK® Flat Package
- $\pm 15$ -V Analog Signal Range
- Trench Isolation Gurads Against Latch-Up
- Break Before Make Switching
- Low On-Resistance  $R_{ON} < 45\Omega$
- Fast Switching  $t_{ON} < 175ns$
- Dual Supply  $t_{OFF} < 145ns$
- Ultra Low Power- $P_D$ : 0.35mW
- TTL, CMOS Compatible
- Single Supply Capability

## DESCRIPTION:

Space Electronics' 411RP (RP for RAD-PAK®) monolithic quad analog switches are designed to provide high speed, low error switching of precision analog signals. Combining low power (0.35 mW) with high speed ( $t_{ON}$ : 175 ns), the 411RP is ideally suited for space applications. The 411RP achieves high-voltage ratings and superior switching performance by employing a high voltage silicon gate process technology. An epitaxial layer prevents latch-up. Each switch conducts equally well in both directions when on, and blocks input voltages up to the supply levels when off. All switches exhibit break before make switching action for use in multiplexer application. The 411RP responds to opposite control logic as shown in the Truth Table. The patented radiation hardened RAD-PAK® technology incorporates radiation shielding in the microcircuit package. It provides a 100krad (Si) Total Dose survivability, based on GEO type orbit (actual TID tolerance is dependent upon orbit and mission duration). It eliminates box shielding while providing lifetime in orbit. This product is available in class B and S packaging and screening.

**TABLE 1. 411RP DUAL SUPPLY ELECTRICAL CHARACTERISTICS**(V<sub>DD</sub> = +15V±10%, V<sub>L</sub> = +5V±10%, GND = 0V, TA = -55 to +125°C UNLESS OTHERWISE SPECIFIED.)

| PARAMETER                                               | TEST CONDITIONS                                                                | +25°C  | -55°C To + 125°C                   | UNITS  |
|---------------------------------------------------------|--------------------------------------------------------------------------------|--------|------------------------------------|--------|
| <b>ANALOG SWITCH</b>                                    |                                                                                |        | V <sub>DD</sub> to V <sub>SS</sub> | V      |
| Analog Signal Range <sup>1</sup>                        | V <sub>D</sub> =±8.5 V, I <sub>S</sub> =-10mA                                  | 25     |                                    | Ω typ  |
| RON                                                     | V <sub>DD</sub> =+13.5V, V <sub>SS</sub> =-13.5V                               | 35     | 45                                 | Ω max  |
| <b>LEAKAGE CURRENTS</b>                                 | V <sub>DD</sub> = +16.5 V, V <sub>SS</sub> = -16.5V                            |        |                                    |        |
| Source OFF Leakage I <sub>S</sub> (OFF)                 | V <sub>D</sub> = + 15.5V, V <sub>S</sub> = 15.5V                               | ±0.1   |                                    | nA typ |
|                                                         | Test Circuit 2                                                                 |        | ±20                                | nA max |
| Drain OFF Leakage I <sub>D</sub> (OFF)                  | V <sub>D</sub> = ± 15.5 V, V <sub>S</sub> =±15.5V;                             | ±0.1   |                                    | nA typ |
|                                                         | Test Circuit 2                                                                 |        | ±20                                | na max |
| Channel ON Leakage I <sub>D</sub> , I <sub>S</sub> (ON) | V <sub>D</sub> = V <sub>S</sub> =±15.5V                                        | ±0.1   |                                    | nA typ |
|                                                         | Test Circuit 3                                                                 |        | ±40                                | nA max |
| <b>DIGITAL INPUTS</b>                                   |                                                                                |        |                                    |        |
| Input High Voltage, V <sub>INH</sub>                    |                                                                                |        | 2.4                                | V min  |
| Input Low Voltage, V <sub>INL</sub>                     |                                                                                |        | 0.8                                | V max  |
| Input Current                                           | V <sub>IN</sub> = V <sub>INL</sub> or V <sub>INH</sub>                         | 0.005  |                                    | mA typ |
| I <sub>IL</sub> or I <sub>IH</sub>                      |                                                                                |        | ±0.5                               | mA max |
| <b>DYNAMIC CHARACTERISTICS</b>                          |                                                                                |        |                                    |        |
| t <sub>ON</sub>                                         | R <sub>L</sub> = 300Ω, C <sub>L</sub> = 35pF                                   | 110    |                                    | ns typ |
|                                                         | V <sub>S</sub> =±10V; Test Circuit 4                                           |        | 175                                | ns max |
| t <sub>OFF</sub>                                        | R <sub>L</sub> = 300Ω, C <sub>L</sub> = 35pF                                   | 100    |                                    | ns typ |
|                                                         | V <sub>S</sub> =±10V; Test Circuit 4                                           |        | 145                                | ns max |
| Charge Injection <sup>1</sup>                           | V <sub>S</sub> =0 V, R <sub>S</sub> =0Ω, C <sub>L</sub> =10 nF; Test Circuit 6 | 5      |                                    | pC typ |
| OFF Isolation                                           | R <sub>L</sub> =50Ω, C <sub>L</sub> =5 pF, f=1MHz; Test Circuit 7              | 68     |                                    | dB typ |
|                                                         |                                                                                | 85     |                                    |        |
| CS (OFF)                                                | f=1MHz                                                                         | 9      |                                    |        |
| CD (OFF)                                                |                                                                                | 9      |                                    | pF typ |
| CD, CS (ON)                                             |                                                                                | 35     |                                    |        |
| <b>POWER REQUIREMENTS</b>                               | V <sub>DD</sub> = +16.5 V, V <sub>SS</sub> = -16.5V                            |        |                                    |        |
| I <sub>+</sub>                                          | Digital Inputs = 0 V or 5V                                                     | 0.0001 |                                    | uA typ |
|                                                         |                                                                                | 1      | 5                                  | uA max |
| I <sub>-</sub>                                          |                                                                                | 0.0001 |                                    | uA typ |
|                                                         |                                                                                | 1      | 5                                  | uA max |
| I <sub>L</sub>                                          |                                                                                | 0.0001 |                                    | uA typ |
|                                                         |                                                                                | 1      | 5                                  | uA max |

1. Guaranteed by design.

**TABLE 2. 411RP SINGLE SUPPLY ELECTRICAL CHARACTERISTICS**

( $V_{DD} = +15V \pm 10\%$ ,  $V_L = +5V \pm 10\%$ ,  $GND = 0V$ ,  $T_A = -55$  to  $+125^\circ C$  UNLESS OTHERWISE SPECIFIED.)

| PARAMETER                              | TEST CONDITIONS                                              | +25°C     | -55°C To 125°C | UNITS        |
|----------------------------------------|--------------------------------------------------------------|-----------|----------------|--------------|
| <b>ANALOG SIGNAL RANGE<sup>1</sup></b> | 3.0 - 8.0V                                                   |           | 0V to $V_{DD}$ | V            |
| $R_{ON}$                               | $0 < V_D = 8.5V$ , $I_S = -10$ mA;                           | 40        |                | $\Omega$ typ |
|                                        | $V_{DD} = +10.8V$                                            | 80        | 100            | $\Omega$ max |
| <b>LEAKAGE CURRENTS</b>                | $V_{DD} = +13.2V$                                            |           |                |              |
| Source OFF Leakage $I_S$ (OFF)         | $V_D = 12.2/1V$ , $V_S = 1/12.2V$                            | $\pm 0.1$ |                | nA typ       |
|                                        | Test Circuit 2                                               |           | $\pm 20$       | nA max       |
| Drain OFF Leakage $I_D$ (OFF)          | $V_D = 12.2/1V$ , $V_S = 1/12.2$                             | $\pm 0.1$ |                | nA typ       |
|                                        | Test Circuit 2                                               |           | $\pm 20$       | nA max       |
| Channel ON Leakage $I_D$ , $I_S$ (ON)  | $V_D = V_S = +12.2V/+1V$ ;                                   | $\pm 0.1$ |                | nA typ       |
|                                        | Test Circuit 3                                               |           | $\pm 40$       | nA max       |
| <b>DIGITAL INPUTS</b>                  |                                                              |           |                |              |
| Input High Voltage, $V_{INH}$          |                                                              |           | 2.4            | V min        |
| Input Low Voltage, $V_{INL}$           |                                                              |           | 0.8            | V max        |
| Input Current                          |                                                              |           |                |              |
| $I_{INL}$ or $I_{INH}$                 | $V_{IN} = V_{INL}$ or $V_{INH}$                              | 0.0005    |                | mA typ       |
|                                        |                                                              |           | $\pm 0.5$      | mA max       |
| <b>DYNAMIC CHARACTERISTICS</b>         |                                                              |           |                |              |
| $T_{on}$                               | $R_L = 300\Omega$ , $C_L = 35$ pF;                           | 175       |                | ns typ       |
|                                        | $V_S = +8V$ ; Test Circuit 4                                 |           | 250            | ns max       |
| $T_{off}$                              | $R_L = 300\Omega$ , $C_L = 35$ pF                            | 95        |                | ns typ       |
|                                        | $V_S = +8V$ ; Test Circuit 4                                 |           | 125            | ns max       |
| Charge Injection <sup>1</sup>          | $V_S = 0V$ , $R_S = 0\Omega$ , $C_L = 10$ nF; Test Circuit 6 | 25        |                | pC typ       |
| <b>POWER REQUIREMENTS</b>              | $V_{DD} = +13.2V$ , Digital Inputs = 0V or 5V                |           |                |              |
| $I_+$                                  |                                                              | 0.0001    |                | mA typ       |
|                                        |                                                              | 1         | 5              | mA max       |
| $I_L$                                  |                                                              | 0.0001    |                | mA typ       |
|                                        | $V_L = +5.25V$                                               | 1         | 5              | mA max       |

1. Guaranteed by design.

## 411RP TYPICAL PERFORMANCE CHARACTERISTICS

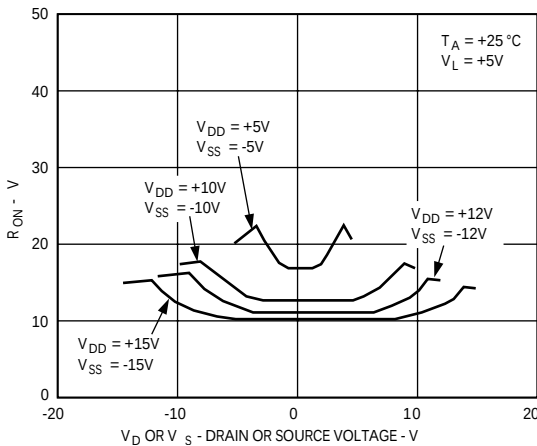


Figure 1. On Resistance as a Function of  $V_D$  ( $V_S$ ) Dual Supplies

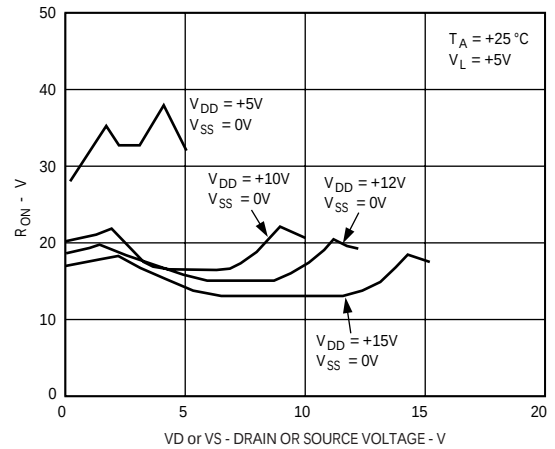


Figure 4. On Resistance as a Function of  $V_D$  ( $V_S$ ) Single Supply

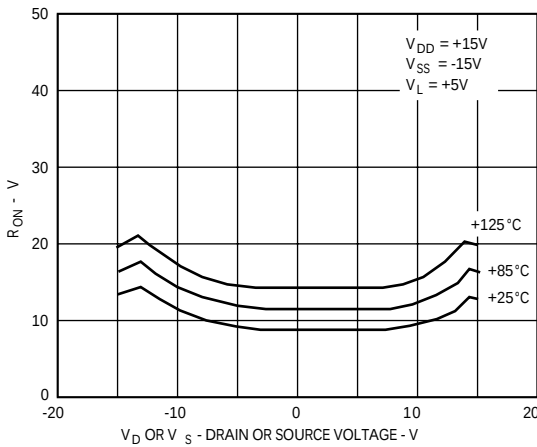


Figure 2. On Resistance as a Function of  $V_D$  ( $V_S$ ) for Different Temperatures

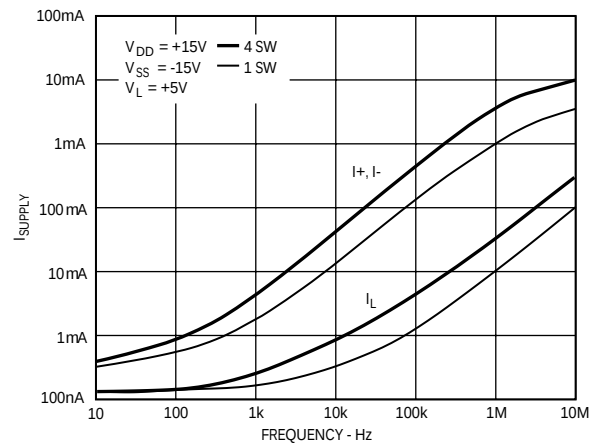


Figure 5. Supply Current vs. Input Switching Frequency

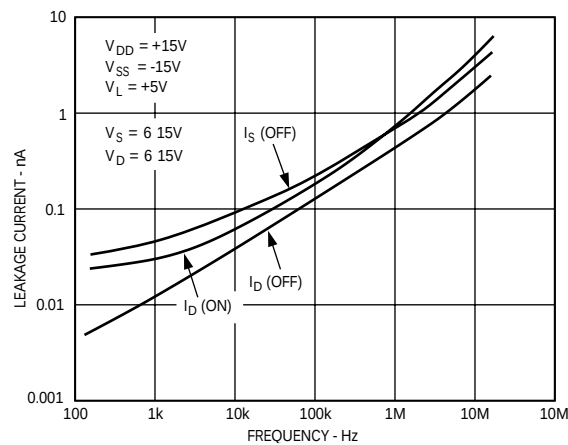


Figure 3. Leakage Currents as a Function of Temperature

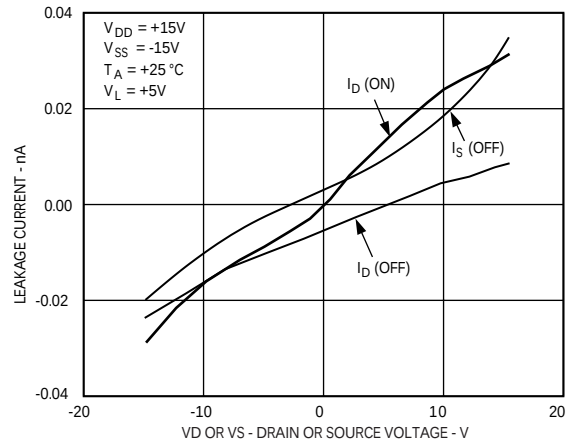


Figure 6. Leakage Currents as Function of  $V_D$  ( $V_S$ )

### 411RP TYPICAL PERFORMANCE CHARACTERISTICS

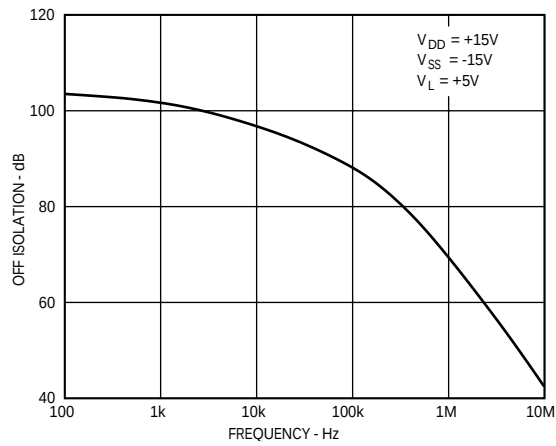


Figure 7. Off Isolation vs. Frequency

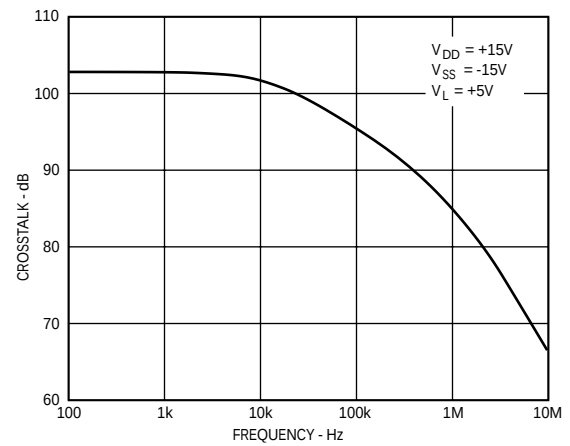
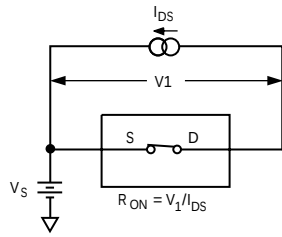
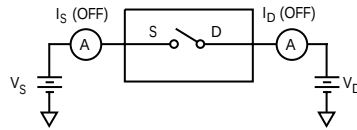


Figure 8. Crosstalk vs. Frequency

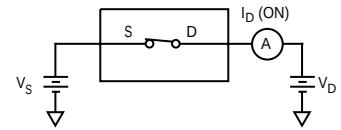
## 411RP TEST CIRCUITS



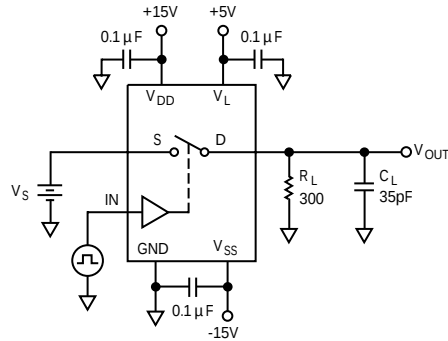
Test Circuit 1. On Resistance



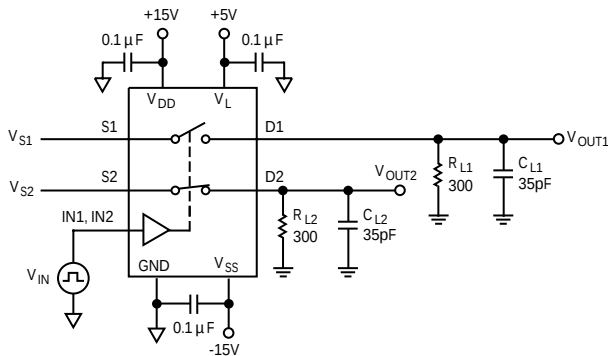
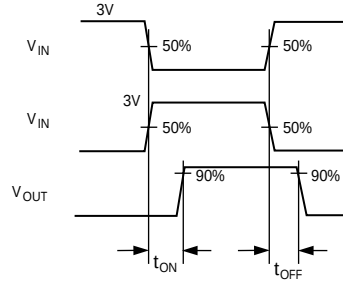
Test Circuit 2. Off Leakage



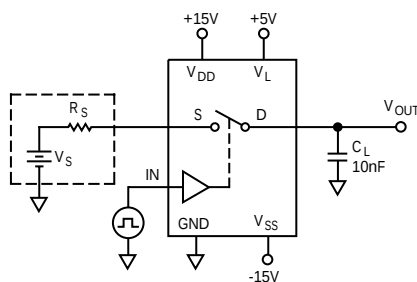
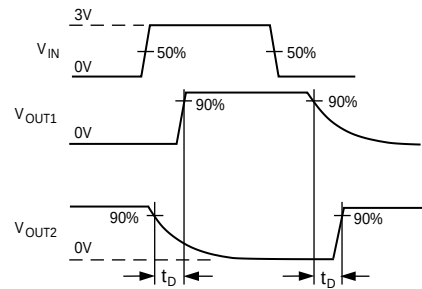
Test Circuit 3. On Leakage



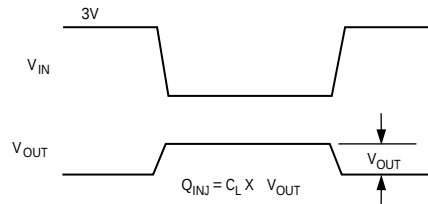
Test Circuit 4. Switching Times



Test Circuit 5. Break-Before-Make Time Delay

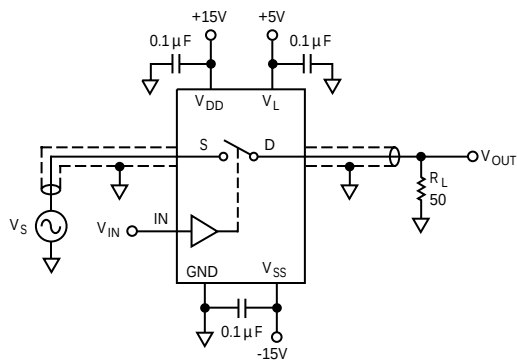


Test Circuit 6. Charge Injection

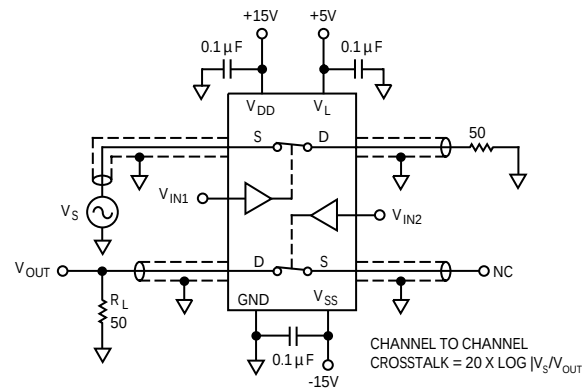


## QUAD SPST CMOS ANALOG SWITCHES

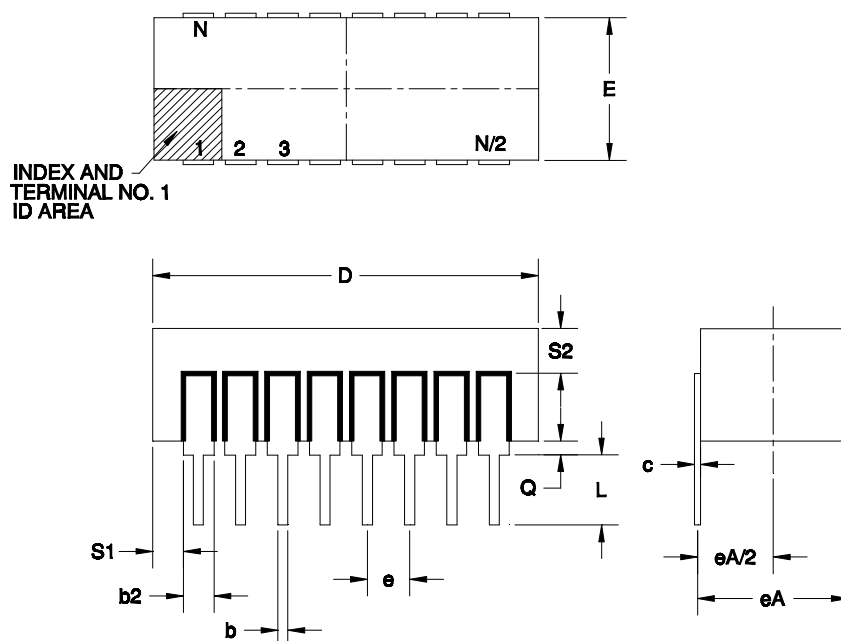
## 411RP TEST CIRCUITS



### Test Circuit 7. Off Isolation



### Test Circuit 8. Channel-to-Channel Crosstalk



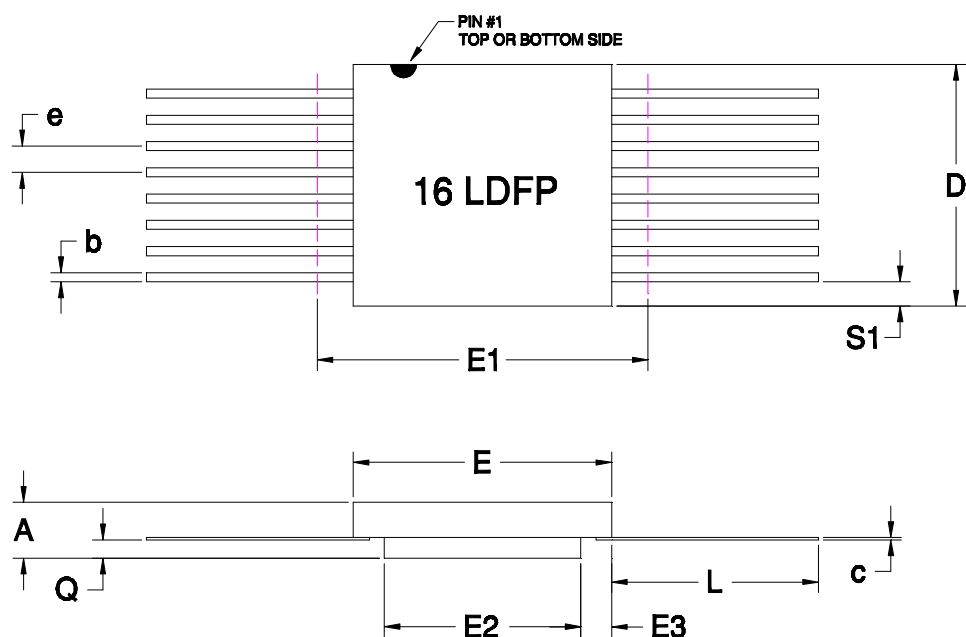
## 16-PIN RAD-PAK® DUAL IN-LINE PACKAGE

| SYMBOL | DIMENSION |       |       |
|--------|-----------|-------|-------|
|        | MIN       | NOM   | MAX   |
| A      | --        | 0.157 | 0.200 |
| b      | 0.014     | 0.018 | 0.026 |
| b2     | 0.045     | 0.047 | 0.065 |
| c      | 0.008     | 0.010 | 0.018 |
| D      | --        | 0.800 | 0.840 |
| E      | 0.220     | 0.295 | 0.310 |
| eA     | 0.300 BSC |       |       |
| eA/2   | 0.150 BSC |       |       |
| e      | 0.100 BSC |       |       |
| L      | 0.135     | 0.145 | 0.155 |
| Q      | 0.000     | 0.002 | 0.060 |
| S1     | 0.005     | 0.027 | --    |
| S2     | 0.005     | --    | --    |
| N      | 16        |       |       |

D16-01

Note: All dimensions in inches.





16-PIN RAD-PAK® FLAT PACKAGE

| SYMBOL | DIMENSION |       |       |
|--------|-----------|-------|-------|
|        | MIN       | NOM   | MAX   |
| A      | 0.117     | 0.130 | 0.143 |
| b      | 0.015     | 0.017 | 0.022 |
| c      | 0.004     | 0.005 | 0.009 |
| D      | --        | 0.415 | 0.440 |
| E      | 0.245     | 0.280 | 0.285 |
| E1     | --        | --    | 0.315 |
| E2     | 0.130     | 0.156 | --    |
| E3     | 0.030     | 0.062 | --    |
| e      | 0.050 BSC |       |       |
| L      | 0.325     | 0.335 | 0.345 |
| Q      | 0.020     | 0.033 | 0.045 |
| S1     | 0.005     | 0.024 | --    |
| N      | 16        |       |       |

F16-01

Note: All dimensions in inches.

**Important Notice:**

These data sheets are created using the chip manufacturers published specifications. Space Electronics verifies functionality by testing key parameters either by 100% testing, sample testing or characterization.

The specifications presented within these data sheets represent the latest and most accurate information available to date. However, these specifications are subject to change without notice and Space Electronics assumes no responsibility for the use of this information.

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